

# Final Test



Amkor는 다양한 TESTER와 HANDLER 및 기타 테스트 관련 장비들을 갖추고 있으며, 향후에도 최신 장비들을 구비하여 고객의 다양한 final test 요구사항을 충족시켜 나아갑니다. Final test는 package된 chip에 대해 양품과 불량률 TESTER와 HANDLER를 이용해 전기적 특성을 검사하는 것을 말합니다.

## Final Test

### Operational Experience

- Fully automated test production environments with excellent services for Mobile AP / Automotive / Memory / PMIC / Wireless Connectivity / CPU / GPU / Network / Sensors

### Technical Supports

- Advanced PKG test solution (PoP / TSV / fcCSP / FCBGA / MEMS)
- High parallelism, Low cost solution with high quality
- Full SW/HW development & failure analysis

### Equipment Capacity

- Full range of test platform for Logic / Mixed / Analog / RF / Memory / SLT
- Various types of handler : Singulated, Strip Test / Film Flame, Sensor Test
- Post-Test Mark and Bake / Scan / Tape & Reel



## Strip Test (Lead Frame)

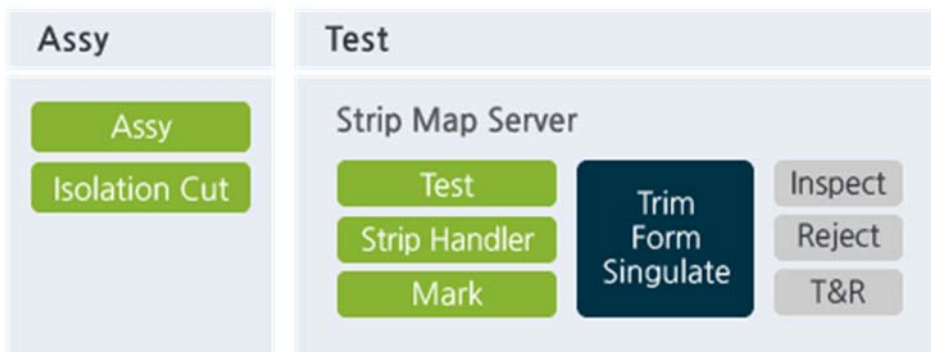
### Operations

- Very High Parallelism
- SOIC / TSSOP / TQFP
- XDLF 600 units per strip

### Test Solution

- Memories
- Serial EEPROM
- Micro-Controller
- Power Management
- OP AMPs

### Process Flow



# Strip Test (Film Frame)

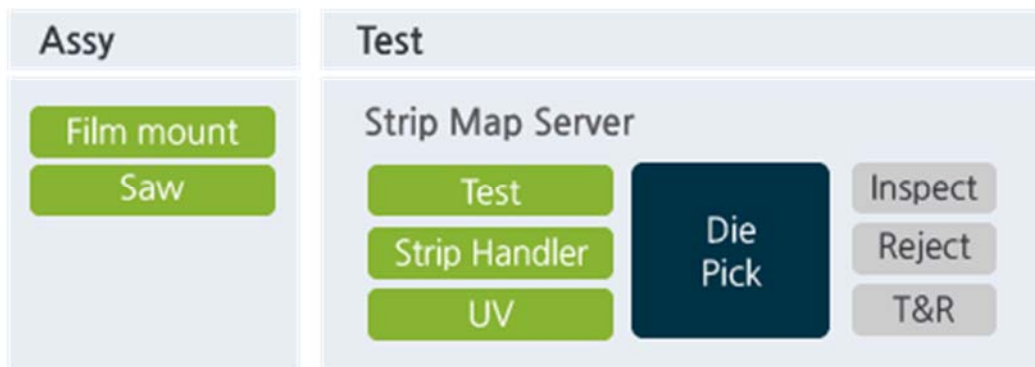
## Operations

- Very High Parallelism
- CK based on Frame Type
- MLF / fcMLF / uCBGA / WLCSP

## Test Solution

- Memories
- Serial EEPROM
- Micro-Controller
- Security Devices
- Connectivity (USB)

## Process Flow



## SLT (System Level Test)

### Operations

- Testing since 2000
- Customized program platform
- PnP type, Chroma / Hontech



Chroma 3260 model

### Test Solution

- Specialized prod service
- Operation improvement
- Handler kit modification

### Current Products

- Mobile AP
- GPU
- Modem
- Programmable Device
- PoP / MeP / TMV / TSV

# Discrete Test

## Operations

- Over 40 years experience

## Test Solution

- Singulated / Strip Test
- Kelvin Test / Single Test

## Current Products

- MOSFET
- IGBT
- Diode
- Regulator IC
- Bipolar Transistor